

Search Notes

Application/Control No.

10/671,592

Examiner

Chris C. Chu

Applicant(s)/Patent under
Reexamination

YAMADA ET AL.

Art Unit

2815

SEARCHED

Class	Subclass	Date	Examiner
257	691, 690, 701, 584 and 678	2/28/2005	C.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Searched in USPAT; US-PGPUB; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	2/28/2005	C.C.
Consulted with David E. Graybill 257/584,690,691,701	2/24/2005	C.C.
Consulted with S. Clark & Roy Potter No search area	2/28/2005	C.C.